

# MICROSCOPY TODAY

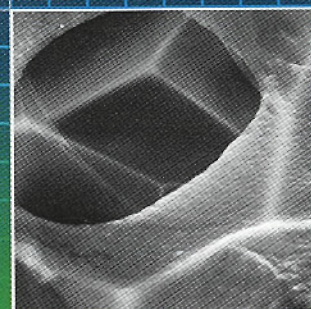
OCTOBER 2000

ISSUE #00-8

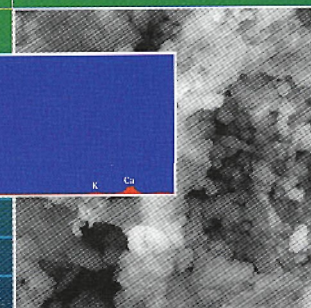
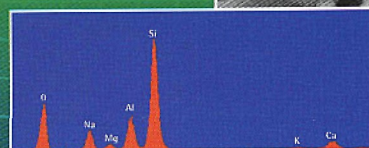


# Ultra-high resolution FESEM Plus Variable Pressure?

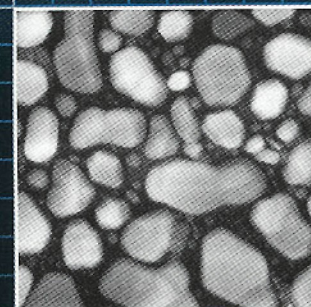
## Have it all – with LEO



Styrofoam, uncoated, 30kV, 1,000x,  
chamber pressure 35 Pa, VPSE detector



Lead oxide, uncoated, 21kV, 10,000x,  
chamber pressure 34 Pa, VPSE detector



Gold on carbon, 30kV, 50,000x,  
chamber pressure 40 Pa, VPSE detector

Two unique innovations, one superb instrument! GEMINI and VPSE! Market leading ultra-high resolution electron optics and Variable Pressure Secondary Electron imaging brought together for the very first time with the new LEO 1530VP.

At last, it is possible to obtain ultra-high resolution imaging and analysis on specimens that are completely non-conducting, moist or outgassing for which a higher chamber pressure avoids time consuming specimen preparation. Specimens such as packaged semiconductor devices, glasses and ceramics, plastics, biological tissues and many more. Features include:

- ▼ Ultra-high resolution in high vacuum mode, at high and low beam energy, using the unique in-lens detector
- ▼ Ultra-high resolution in variable pressure mode, at high and low beam energy, using the patented VPSE detector

Why compromise? For supreme flexibility in ultra high resolution imaging and analysis, you can Have it all with the NEW LEO 1530VP.

USA: New York Tel (1) 914 747 7700 Fax (1) 914 681 7443 E-mail [info@leo-usa.com](mailto:info@leo-usa.com)  
UK: Cambridge Tel (44) 1223 414166 Fax (44) 1223 412776 E-mail [info@leo-em.co.uk](mailto:info@leo-em.co.uk)  
Germany: Oberkochen Tel (49) 73 64 94 6137 Fax (49) 73 64 94 4851 E-mail [info@leo.de](mailto:info@leo.de)

Call Toll Free 800-356-1090

[www.leo-usa.com](http://www.leo-usa.com)

**LEO**  
*The power to resolve*